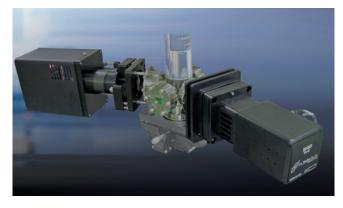
## In-situ M-2000

Spectral ranges			
Model	Spectral range	Number of wavelengths	
٧	370nm to 1000nm	390	
Χ	245nm to 1000nm	470	
X-210	210nm to 1000nm	490	
D*	193nm to 1000nm	500	
"I" - NIR extension**	Up to 1690nm	Additional 200 wavelengths	

- \*) recommended in-situ models: V, VI, X, XI, X-210, XI-210 due to high light density. D, DI still fine for small chambers with short beam path
- \*\*) NIR extension available for all models. Possible to upgrade later in the field

## In-situ package consists of:

- General ellipsometer, including:
  - Input unit with lamp housing, and rotating compensator
  - Receiver unit with analyzer
  - → M-2000 control box (19" rack mount box)
  - → EC-400 control box (19" rack mount box)
- Computer and monitor
- CompleteEASE data acquisition and analysis software
- 1 set (2 pieces) flat fused silica UHV windows,
  2.75" (DN40CF) flange
- 1 set of in-situ mounts and stands to attach the in-situ tilt stages
- 1 set of in-situ tilt stages
- 1 piece of alignment jig
- Single angle ex-situ test base
- 1 set of cables and optical fiber(s), length 3m (standard); longer cables/fibers on request



In-situ M-2000DI mounted to a small chamber

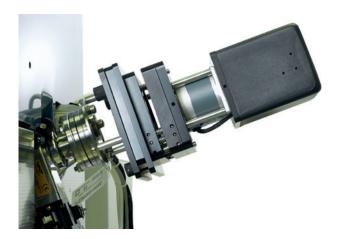






## In-situ M-2000





M-2000 In-situ detector on an atomic layer deposition chamber

Upgrade options require automated angle base (horizontal)			
Ex-situ angle bases			
Automated 100 mm XY mapping			
Automated 200 mm XY mapping			
Automated 300 mm XY mapping			
Manual or automated sample rotator			
Focusing option			
Several liquid cells			
Heating stages (RT to 300 °C or -190 °C to 600 °C)			